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## TABLE OF CONTENTS

Radiation Effects of a 128Mb NOR Type B4-Flash .....	1
<i>Anni Cao, Yuanfu Zhao, Xin Li, Weiyi Cao, Xupeng Han, Xiao Bi</i>	
Bias and LET Dependence of Heavy Ion Induced Degradation in SiC MOSFETs .....	5
<i>Chao Peng, Zhifeng Lei, Zhangang Zhang, Teng Ma, Hong Zhang, Yujuan He</i>	
Research on the Reliability of GaN-Based Power Electronic Devices for Space Applications.....	9
<i>Dongping Yang, Zhiqi Huang, Pengfei Xie, Mi Liu, Chengan Wan</i>	
Exploration of 2D Test for SEE in PLL Devices .....	13
<i>Wang Feng, Tong Zhou</i>	
Total Dose and Heavy Ion Radiation Response of NAND-Like Spin Orbit Torque Device .....	17
<i>Hanbin Wang, Bi Wang, Min Wang, Chenyi Wang, Shixing Li, Yaoyu Li, Zhaohao Wang, Yuanfu Zhao</i>	
Real-Time Soft Error Mitigation System for SRAM-Based FPGAs .....	20
<i>Hanxu Feng, Jing Zhou, Shuo Wang, Zhuoli Wang, Jie Li, Yuanhang Bu, Chunsheng Tian</i>	
A Fault Injection Method for Evaluating Single Event Soft Errors in Deep Neural Networks .....	24
<i>He Lyu, Bo Mei, Pengchao Xue, Bo Wang, Rigen Mo, Qifei Yuan, Wu Gao</i>	
Risk Assessment Method for Single-Event Effects in Aerospace Microsystems Based on Bayesian Networks .....	29
<i>Jiachang Liu, Bo Mei, He Lv, Rongxing Cao, Yuxiong Xue, Yazhou Liu</i>	
Total Ionizing Dose Effect on Voltage Controlled Ring Oscillator in 65nm CMOS .....	33
<i>Jinghao Zhao, Zheyi Li, Xuefeng Yu, Qi Guo, Jeffrey Prinzie, Paul Leroux</i>	
Heavy Ion Irradiation-Induced Electrical Degradation and Leakage Mechanism in Quasi-Vertical GaN PiN Diodes .....	36
<i>Junfan Qian, Feng Zhou, Yiteng Yu, Chongrui Shu, Mai Zhang, Tianqi Wang, Zhengliang Zhang, Hai Lu</i>	
The Radiation Susceptibility of FRAM Induced by Pulsed $\gamma$ -Ray and Reactor Neutron .....	40
<i>Junlin Li, Chao Qi, Ruibin Li, Wei Wu, Wei Chen, Lili Ding, Xiaoming Jin, Xiaoyan Bai, Yan Liu, Chenhui Wang, Weijian Liu, Shilin Yu</i>	
A Single-Event Hardened SiC MOSFET Based on Localized Carrier Lifetime Control Region.....	45
<i>Leshan Qiu, Yun Bai, Yan Chen, Jieqin Ding, Xinyu Liu</i>	
A Physical Simulation Model for Neutron Damage Analysis on Triple Junction GaAs Solar Cell.....	49
<i>Longlong Zhang, Ding Song, Jian Li</i>	
New Observations on Carrier Transport and Thermal Behavior in IGBT During Heavy-Ion Radiation .....	52
<i>Lu Mi, Shiwei Liang, Jiaqi Chene, Liu Yang, Daming Wang, Xinyi Tu, Jun Wang, Wanjun Chen</i>	
Study on Dose Response of 300 nm Gate Oxide Process PMOS .....	56
<i>Mengjun Sun, Jing Sun, Chengfa He, Qi Guo, Lin Wen</i>	

The Imbalance in SEU Sensitivity Among the Bit Positions in the Trainable Parameters of the YOLOv5s Neural Network.....	59
<i>Mingyan Ma, Yaqing Chi, Jianjun Chen, Bin Liang</i>	
Research on Low-Cost In-Orbit Error Rate Assessment Methods for Commercial Space.....	62
<i>Sichong Huang, Tao Dong, Chunliang Gou, Xiao Bi, Hongchao Zheng, Liang Wang</i>	
An Efficient SEU Sensitivity Analysis Method for SOC Processor.....	66
<i>Siqi Wang, Jinhui Liu, Xiaopeng Zhang, Yayu Wang</i>	
Comparative Investigation on TID-Induced Threshold Voltage Shift for 1200V Asymmetric Trench SiC MOSFET by Experiment and Simulation.....	70
<i>Tao Liu, Rongyao Ma, Zhiyu Wang, Qian Liu, Hongshen Wang, Jian Shen, Juan Luo, Shengdong Hu</i>	
Radiation Effects Modeling and Analysis in RRAM-Based In-Memory Computing Systems .....	74
<i>Tingrui Ren, Xypeng Han, Kexin Yao, Huimeng Guo, Liang Wang, Yuanfu Zhao, Bi Wang</i>	
SEE Characterization of nor Flash in Dynamic Operation Mode for Aerospace Application .....	78
<i>Wei Cao, Lei Chen, Jiancheng Li, Qichao Zha, Xin Li, Fubang An, Lifeng Qi, Yimao Cai</i>	
Research on a Method for Evaluating SEL and SEU in a Time-Interleaved High-Speed ADC .....	82
<i>Wei Jiang, Yafeng Wei, Xianchao Wen, Zhou Yu, Dongbin Fu, Tianqi Wang</i>	
Research on High-Voltage High-Power Aerospace Full-Bridge DC-DC Converter Based on SiC.....	88
<i>Weiguang Wang, Pengfei Xie, Mi Liu, Mingming Ji, Kun Zhang, Dongping Yang</i>	
A Radiation-Hardened Resistive Random Access Memory with High-Reliability Write and Read Scheme .....	93
<i>Weiyi Cao, Yajiao Liu, Chenglong Sui, Anni Cao, Kexin Yao, Tingrui Ren, Xupeng Han, Liang Wang, Bi Wang, Yuanfu Zhao</i>	
Study on the Displacement-Total Ionizing Dose Synergistic Effect of UC1825 Pulse Width Modulator.....	98
<i>Xiang Zhang, Zhiming Zhao, Yiyuan Wang, Hua Zhang, Zhen Lv, Lindong Ma, Sihan Wang</i>	
Research on Reliability Enhancement Technology of Real-Time Operating System.....	103
<i>Xiaochuan Shuang, Jie Wei, Jianwei Niu, Shuyi Feng, Liang Bai, Hongjun You, Wenbo Tian</i>	
2D TCAD Simulation of Transient Dose Rate Effect in 130nm SOI CMOS Inverters .....	107
<i>Xiuyu Zhang, Yangli Xin</i>	
Experimental Study on SEL of a COTS 3D NAND Flash Memory and SEL Protection.....	112
<i>Xuesong Zheng, Yuhang Wang, Rigen Mo, Zhichao Wei, Bo Mei, Chaoming Liu, Mingxue Huo, Liyi Xiao</i>	
A High-Resolution Algorithm for Extracting Time Constant Spectra Based on Frequency-Dependent Capacitance Measurements .....	115
<i>Y. Q. Zhang, J. L. Zhang, M. L. Ji, G. J. Wang, Y. H. Zhong</i>	
Quantitative Analysis of Irradiation-Induced MOSFET Interface Traps using Subthreshold and C-V Characteristics .....	118
<i>Yanfang Li, Zhongyang Li, Yanyong Wang, Tengfei Li, Liang He, Maolin Zhang</i>	
Angular Sensitivity of Heavy-Ion-Induced Single-Event Transient Pulse Widths for Bulk FinFET Technology .....	121
<i>Yang Bai, Tongde Li, Yongqin Zhu, Yu Sun, Jingshuang Yuan, Liang Wang</i>	

Investigation of Secondary Hadronic Radiation Effects from GCRs at 1–10 GeV/n with High Energy Physics Model.....	125
<i>Ying Wang, Lin Wen, Cheng-Fa He, Wu Lu, Yu-Dong Li, Qi Guo</i>	
Proton-Induced Single-Event Upset Characterization in FinFET and FDSOI D-Flip-Flops.....	129
<i>Yongqin Zhu, Tongde Li, Yang Bai, Qian Du, Liang Wang</i>	
Thin-Film LiNbO <sub>3</sub> Modulator Exploration of Aerospace Applications.....	132
<i>Y. P. Chen, H. Tang, R. F. Wang, X. Y. Qiu, B. Zhou</i>	
A Comparative Study of Total Ionizing Dose and Heavy-Ion Irradiation Effects on n-Channel and p-Channel SGT MOSFETs.....	136
<i>Yuan Wang, Xiaozong Huang, Rui Yang, Jie Jiang, Fan Xiang, Feng Yang</i>	
Radiation Effects on the Reliability of SRAM Physical Unclonable Functions.....	139
<i>Yujia Li, Chengde Dong, Huimeng Guo, Chunqing Yu, Zengqiang Zhang, Xin Ma, Liang Wang, Yuanfu Zhao</i>	
Failure Mechanism and Layout Reinforcement for Enhancing Single-Event Tolerance in 4H-Silicon Carbide Inverters.....	143
<i>Yurui Yang, Yong Gu, Jie Ma, Long Zhang, Siyang Liu, Weifeng Sun</i>	
Anti-Radiation Reinforcement Design and Evaluation Methods of High-Performance A/D Converter for Aerospace.....	146
<i>Zhichao Wei, Ran Zheng, Bo Wang, Zhibo Yang, Yi Sun, Bo Mei</i>	
Experimental Analysis of Effects of JFET Region on Single-Event Gate Damage Induced by Heavy Ion in SiC MOSFETs.....	150
<i>Zhiwen Zhang, Qingwen Song</i>	
Development of a Self-Shielded D-D Neutron Generator.....	153
<i>Zixu Liu, Hongtao Chen, Kai Zhang, Qi Sun, Xuesheng Jiao, Qinghua Huang, Yingmin Song, Fang Zhao, Kun Zhang, Xingyu Liu, Xinbao Gong, Guangxu Zhou, Zongyu Song, Xinxin Li</i>	
Investigation of Electrical Performance Degradation and Trap States in Depletion-Mode Metal-Insulator-Semiconductor (MIS) GaN HEMTs Under Heavy Ion Irradiation.....	159
<i>Can Zou, Yiteng Yu, Peipei Hu, Hai Lu, Feng Zhou, Chongrui Shu, Pengfei Zhai, Junfan Qian, Mai Zhang, Jie Liu</i>	
Study on Motor Control Circuit Burnout Induced by Space Electrostatic Discharge and Single Event Effect.....	163
<i>Run-Jie Yuan, Rui Chen, Jianwei Han, Yanan Liang, Zicai Shen, Qizheng Ji, Ziyu Wang, Hailong Yu</i>	

**Author Index**